

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/081,598 | Applicant(s)/Patent Under Reexamination HILLE ET AL | |
| | Examiner Jacob Y Choi | Art Unit 2875 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-6068384 | 05-2000 | Tyson et al. | 362/153.1 |
| | B | US-5908236 | 06-1999 | Lueken et al. | 362/364 |
| | C | US-5823664 | 10-1998 | Demshki, Jr. et al. | 362/366 |
| | D | US-5230559 | 07-1993 | Porter et al. | 362/153.1 |
| | E | US-5887966 | 03-1999 | Eissner et al. | 362/153.1 |
| | F | US-6036337 | 03-2000 | Belfer | 362/287 |
| | G | US-5144540 | 09-1992 | Hayes | 362/268 |
| | H | US-4712168 | 12-1987 | Scherrer | 362/427 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.